



XRF-Spectrometer LD-LXRF-A11

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Overview

The Labodam XRF-Spectrometer LD-LXRF-A11 is designed for non-destructive elemental analysis of precious metals in jewellery and other sample materials. Using X-ray fluorescence technology, the instrument identifies elements through their characteristic secondary X-ray emissions and determines their concentration from the measured fluorescence intensity.

Features:

- Non-destructive X-ray fluorescence analysis for rapid elemental identification and quantification
- Supports analysis of more than 60 elements from potassium (K) to uranium (U)
- Si PIN semiconductor detector provides elemental X-ray detection
- Single sample chamber simplifies sample placement and measurement
- Integrated X-ray tube, amplifier circuit, and high- and low-voltage power supplies
- Non-Vacuum chamber supports the X-ray measurement system
- Element concentrations are determined through calibrated X-ray fluorescence intensity
- Designed for precious-metal analysis, including platinum, palladium, rhodium, gold, iridium, and other alloying elements

Applications:

Suitable for elemental analysis of precious-metal jewellery, metal alloys, powders, solids, and liquids in jewellery manufacturing, precious-metal testing, quality control, material analysis, laboratories, and research applications.

Specifications:

Weight	20 kg
Power Supply	AC 110/220 V
X-Ray Source	X-Ray Tube
Measurement Time	60–300s
Measurement Range	1 ppm–99.99%
Measuring Objects	Powder, Solid and Liquid
Relative Humidity	?70%
Measurement Precision	0.05% (>96%)
Ambient Temperature Range	15–30°C
Analytical Range of Elements	More than 60 elements, K to U